

Search Notes



Application/Control No.

10/761,055

Examiner

David M. Naff

Applicant(s)/Patent under
Reexamination

BAYON ET AL.

Art Unit

1651

SEARCHED

| Class | Subclass | Date | Examiner |
|---------|----------|---------|----------|
| 435 | 124 | 3/23/05 | one |
| | 127 | | |
| | 180 | | |
| | 182 | | |
| | 395 | | |
| | 397 | | |
| | 398 | | |
| | 402 | | |
| 424 | 423 | | |
| | 426 | | |
| | 444 | | |
| | 4307 | | |
| 530 | 350 | | |
| | 402 | | |
| | 402 | | |
| 606 | 181 | | |
| 800 | 41 | | |
| to date | | 8/9/05 | one |
| to date | | 10/5/05 | one |

INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
|--------------|----------|---------|----------|
| PG Pub | | 10/5/05 | one |
| See printout | | | |
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)

| | DATE | EXMR |
|----------------------|---------|------|
| 09/554509 | 3/23/05 | one |
| West See printout | 8/9/05 | one |
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